ACME Electronics Corporation
越峰電子材料股份有限公司

客戶 CUSTOMER　Platan　　日 期 DATE　2024.6.18

認　可　書
SPECIFICATION FOR APPROVAL

客戶品名 CUSTOMER P/N	
越峰品名 ACME P/N	P41I93*28*30
認可書編號 SPEC. NO.	

越峰電子 ACME 產品承認

為保證訂單順利完成，請在一個月內簽回。否則，將默認貴司同意依此份認可書內容製作您所有此規格的訂單產品。

In order to ensure the leadtime for your order, pls confirm and sign this spec for ACME within one month while you received it. Or else, it means that you have approved this spec, and you have agreed with that ferrite cores from your order be produced according to this spec.

客戶認可　APPROVED BY：

如有客戶品碼（料號），請填寫在下
客戶品碼（料號）：
CUSTOMER P/N

承認書製作廠別 Factory
■廣州廠：越峰電子(廣州)有限公司 / 中國廣東省廣州增城市增江街東區府前路1號
No.1 Fuqian East Road, Zengjiang Street East Square, Guangzhou-Zengcheng City, 511300, Guangdong Province, China
Tel: +86-20-3285-1888:　Fax: +86-20-3285-1666
■昆山廠：越峰電子(昆山)有限公司 / 中國江蘇省昆山市黃浦江北路533號
No.533 Huangpujiang North Rd., Kunshan City, 215337, Jiang-Su Province, China
Tel: +86-512-5793-2888:　Fax: +86-512-5766-4667

批准	審核	擬制
APPROVED BY	CHECKED BY	PREPARED BY
Julian Chen	Christina Lv	Guoqi Tu

ACME Electronics Corporation
越峰電子材料股份有限公司

歷史變更記錄
REVISION RECORDS LIST

客戶CUSTOMER: Platan	P/N	P41I93*28*30
	SPEC./N	

I .更改記綠 REVISION RECORD:

版本號 REV. NO.	更改內容及原因 CONTENTS AND REASONS	日期 DATE OF APPROVAL	擔當 DRAWN
1	新制 NEW RELEASE	2024.6.18	Guoqi Tu

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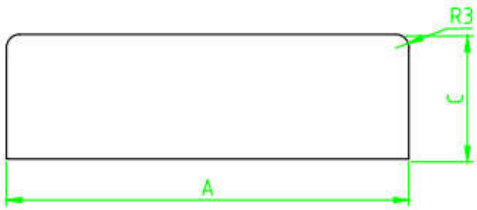
規格書名稱/Specifications :P41I93*28*30	客戶料號/Customer P/N：

一、形狀、尺寸、材質/Shape, dimensions & material：

(1)形狀、尺寸：如下圖所示(單位：mm)Shape & dimensions：

(2)材質Material：P41

圖例/Drawing：



尺寸規格/Dimensions：

A：	93±1.80
C：	28±0.50
I：	30±0.50

二、電磁特性規格 Electrical Characteristics：

材質 Material	初導磁率ui Initial Permeability
P41	2400±25%

注意事項: Remarks

1. C、I尺寸等邊研磨。 The dimensions of C、I need to be grinded.

ACME 外觀標準(I core)
ACME Products Appearance Specification(I core)

1.缺角，脫帽(chip, uncap)

尺寸 Core size(A)	單點最大面積 Max.size/point（mm^2）	總面積 total area(mm2)
A≤10mm	1.0	3
10＜A≤20mm	2.0	6
20＜A≤30mm	2.5	7.5
30＜A≤50mm	3.5	10.5
A＞50mm	0.1*A	0.1*A*3

—— 小於最大點面積的缺角/脫帽以總面積進行判定。The cumulative area of chip, uncap less than the total area is allowable.

——單點面積小於0.5mm2的不做統計。The defect won't be counted which area less than 0.5mm^2.

2. 裂（Crack）：

參照國際電工.標準:IEC-60424

This Specification is based on IEC－60424。

3.結晶（Crystallites）

尺寸 Core size(A)	單點最大面積 Max.size/point（mm^2）	每個面的結晶總面積 total area each surface(mm2)
A≤10mm	2.0	4
10＜A≤20mm	3.0	6
20＜A≤30mm	4.0	8
30＜A≤50mm	5.0	10
A＞50mm	0.25*A	0.25*A*2

—— 小於最大點面積的結晶以總面積進行判定。The cumulative area of chip, uncap less than the total area is allowable.

——單點面積小於1.0mm2的不做統計。The defect won't be counted which area less than 1.0mm^2.

4. 粘膜 （Sticking ）：

(1) 面積：≦1/4所在面面積。area: less than the 1/4 of respective surface.

(2) 深度: ≦ 0.2mm。Depth: ≤0.2mm

5.毛邊（ Ragged edge）：

(1)高度:不超過該尺寸面為判定基准。 Height: It is not permitted exceed the respective surface dimension.

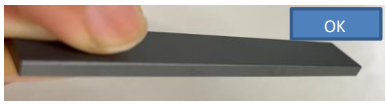
(2) 長度:≦1/4發生面的周長。Length: It is permitted up to 1/4 of surface perimeter.

6.刮傷（Scrape）：

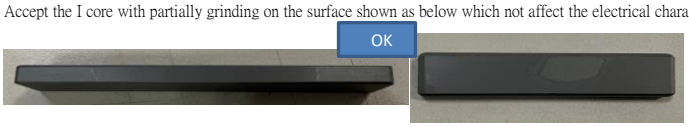
刮傷可接受。 Scrapes are allowed on surface.

7.其他 others:

(1) 研磨後倒角不均勻，部分無倒角可接受，如下。
Due to grinding process, the chamfer is not uniform and equal. It is accepted without no chamfer partially.



(2)部分研磨可接受，如下。
Accept the I core with partially grinding on the surface shown as below which not affect the electrical characteristics of core.



(3) 刷膠痕 glue trace ：不會影響電器特性和機械強度。

It occurs on contact surface of core without grinding progress.

The contamination do not have any influence on the electrical behavior, on the mechanical strength and is only present on the surface.

備註 Remark:

1.以上標準之制定參照國際電工標準：IEC-60424。This Specification is based on IEC－60424。

2.以上標準未詳盡之處仍以IEC電工標準為參照依據。
The other details that not be mentioned in this document are referred to IEC－60424 too.

3.抽樣計劃採用 MIL-STD-105E表(II)次水準,單次抽樣計劃AQL=1.0
The sampling is according to MIL-STD-105E, verification level II is used and AQL=1.0.

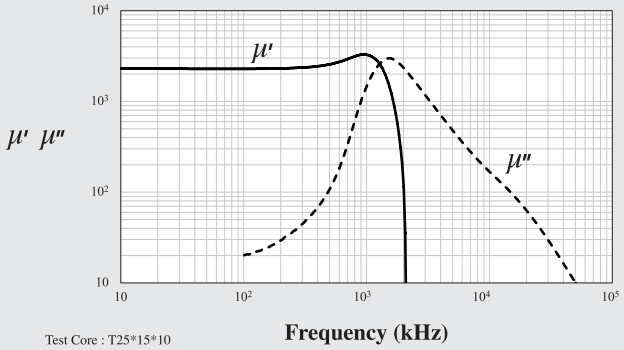
ACME Electronics(Kunshan)Co.,Ltd.
Product Approval

TESTED BY: Christina Lv CHECKED BY: Ivan Meng APPROVED BY: Julian Chen

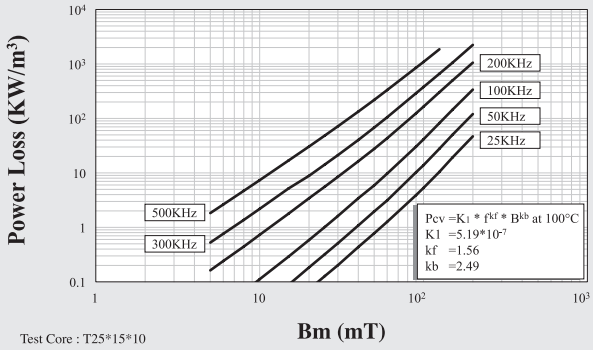
	Symbol	Unit	Measuring Conditions			Conventional Low Loss Material
			Freq.	Flux den.	Temp.	P41
Initial Permeability	μ_i		≤ 10kHz	0.25mT	25°C	2400 ± 25%
Amplitude Permeability	μ_a		25kHz	200mT	25°C	> 4500
					100°C	> 4500
Power Loss	Pv	KW/m³	25kHz	200mT	25°C	125
					100°C	50
			100kHz	200mT	25°C	650
					100°C	350
			300kHz	100mT	25°C	820
					100°C	500
			500kHz	50mT	25°C	400
					100°C	300
Saturation Flux Density	Bs	mT	10kHz	H = 1200A/m	25°C	495
					100°C	395
Remanence	Br	mT	10kHz	H = 1200A/m	25°C	170
					100°C	55
Coercivity	Hc	A/m	10kHz	H = 1200A/m	25°C	13
					100°C	6
Hysteresis Material Constant	η_B	10^{-6}/mT	10kHz	1.5-3.0mT	25°C	< 1
Disaccommodation Factor	D_F	10^{-6}	10kHz	< 0.25 mT	25°C	< 2
Curie Temperature	Tc	°C				≥ 230
Resistivity	ρ	Ωm				4.00
Density	d	g/cm³				4.85

Note: Material characteristics are typical for a toroid core.
Product specification will differ from these data due to the influence of geometry and size.

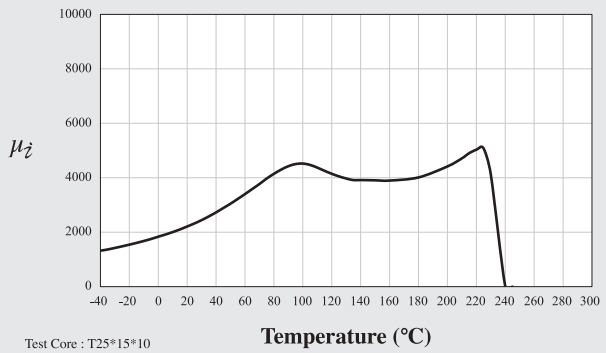
Complex Permeability V.S. Frequency



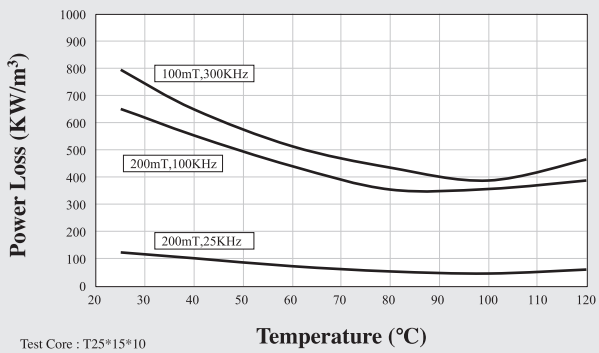
Power Loss V.S. Temperature/Flux Density/Frequency



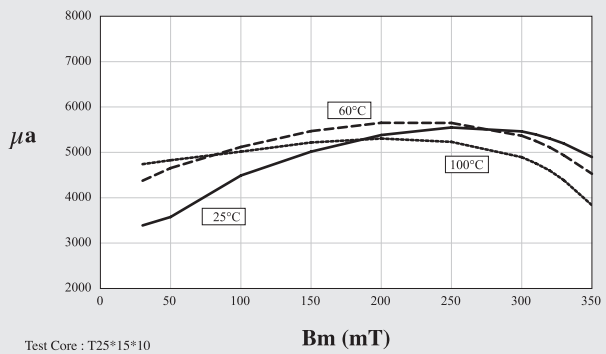
Initial Permeability V.S. Temperature



Power Loss V.S. Temperature



Amplitude Permeability V.S. Flux Density (Bm)



Saturation Flux Density V.S. Magnetic Field